



24 V, EIGHT-CHANNEL DIGITAL-INPUT SERIALIZER

FEATURES

- **Eight Sensor Inputs**
 - High Input Voltage up to 30 V
 - Selectable Debounce Filters From 0 ms to 3 ms
 - Adjustable Current Limits From 0.2 mA to 5.2 mA
 - Field Inputs and Supply Lines Protected to 15-kV HBM
- **Output Drivers for External Status LEDs**
- **Cascadable for More Inputs in Multiples of Eight**
- **SPI-Compatible Interface**
- **Regulated 5-V Output for External Digital Isolator**
- **Over-Temperature and Low-Supply Voltage Indicator**

APPLICATIONS

- **Sensor Inputs for Industrial Automation and Process Control**
 - IEC61131-2 Type 1, 2, or 3 Switches
 - EN60947-5-2 Proximity Switches
- **High Channel Count Digital Input Modules for PC and PLC Systems**
- **Decentralized I/O Modules**

DESCRIPTION

The SN65HVS880 is a 24-V, eight-channel, digital-input serializer for high-channel density digital input modules of PC and PLC based systems in industrial automation. In combination with galvanic isolators the device completes the interface between the 24-V sensor outputs of the field-side and the low-voltage controller inputs at the control-side. Input signals provided by EN60947-5-2 compliant 2- and 3-wire proximity switches are current-limited and then validated by internal debounce filters. The input switching characteristic is in accordance with IEC61131-2 for Type 1, 2, and 3 sensor switches.

Upon the application of load and clock signals, input data is latched in parallel into the shift register and afterwards clocked out serially via a subsequent isolator into a serial PLC input.

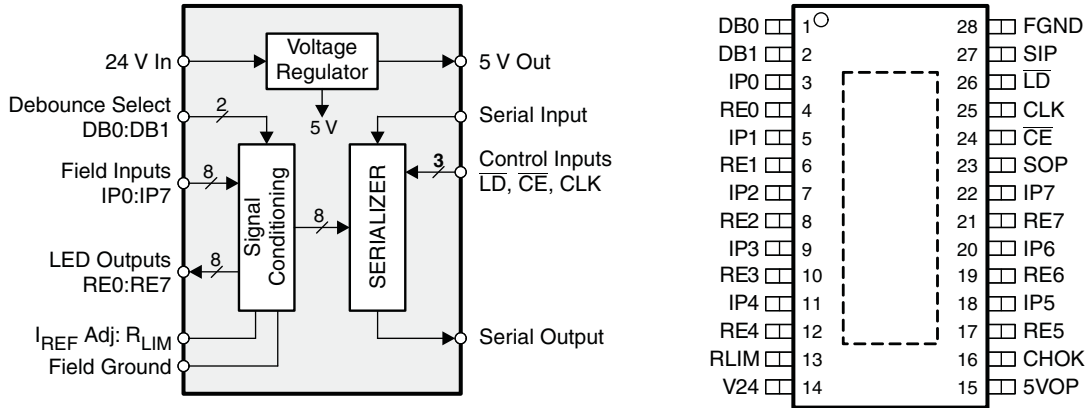
Cascading of multiple SN65HVS880 is possible by connecting the serial output of the leading device with the serial input of the following device, enabling the design of high-channel count input modules. Input status is indicated via 3-mA constant current LED outputs. An external precision resistor is required to set the internal reference current. The integrated voltage regulator provides a 5-V output to supply low-power isolators. An on-chip temperature sensor together with an internal supply voltage monitor provides a chip-okay (CHOK) indication.

The SN65HVS880 comes in a 28-pin PWP PowerPAD™ package allowing for efficient heat dissipation. The device is specified for operation at temperatures from –40°C to 85°C.

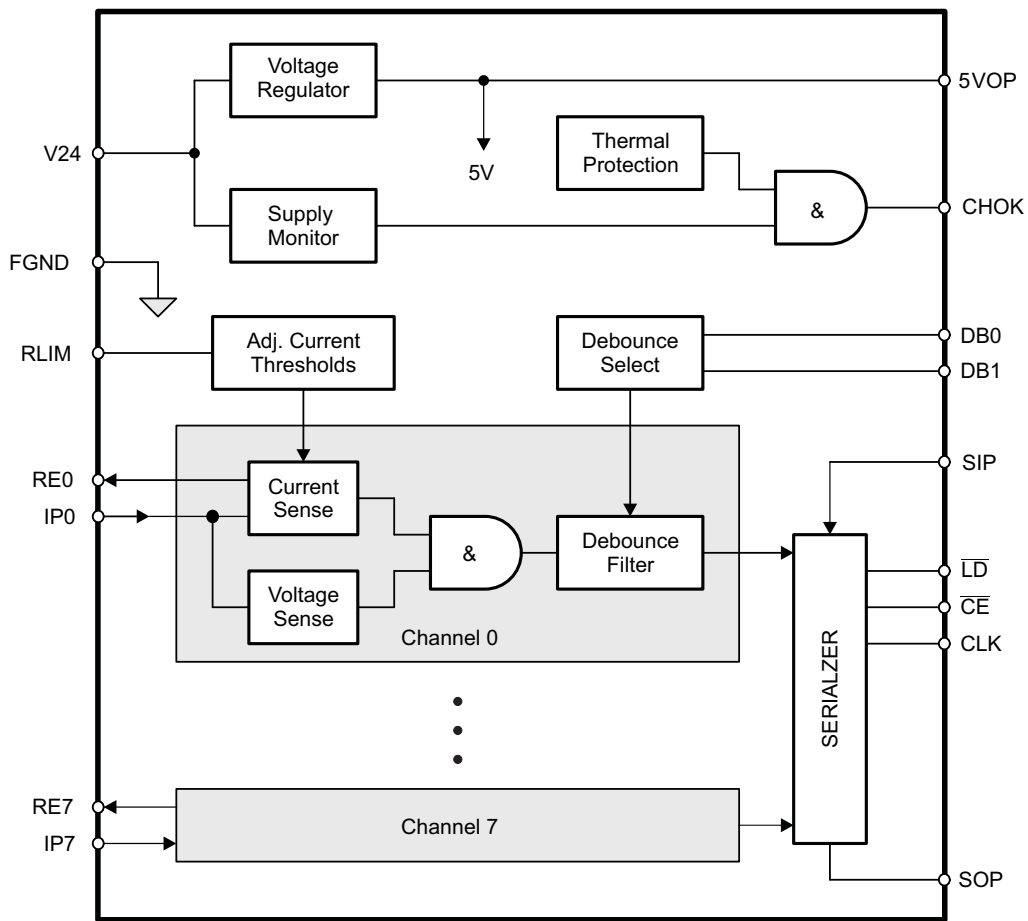


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FUNCTIONAL BLOCK DIAGRAM



TERMINAL FUNCTIONS

TERMINAL		DESCRIPTION
PIN NO.	NAME	
1, 2	DB0, DB1	Debounce select inputs
3, 5, 7, 9, 11, 18, 20, 22	IPx	Input channel x
4, 6, 8, 10, 12, 17, 19, 21	REx	Return path x (LED drive)
13	RLIM	Current limiting resistor
14	V24	24 VDC field supply
15	5VOP	5 V output to supply low-power isolators
16	CHOK	Chip okay indicator output
23	SOP	Serial data output
24	\overline{CE}	Clock enable input
25	CLK	Serial clock input
26	\overline{LD}	Load pulse input
27	SIP	Serial data input
28	FGND	Field ground

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V ₂₄	Field power input	V ₂₄	-0.3	35	V
V _{IPx}	Field digital inputs	IPx	-0.3	35	V
V _{ID}	Voltage at any logic input	DB0, DB1, CLK, SIP, \overline{CE} , \overline{LD}	-0.5	6	V
I _O	Output current	CHOK, SOP		±8	mA
V _{ESD}	Electrostatic discharge	Human-Body Model ⁽¹⁾	All pins	±4	kV
			IPx, V ₂₄	±15	
		Charged-Device Model ⁽²⁾	All pins	±1	kV
			Machine Model ⁽³⁾	All pins	±100
P _{TOT}	Continuous total power dissipation	See Thermal Characteristics table			
T _J	Junction temperature		170		°C

(1) JEDEC Standard 22, Method A114-A.

(2) JEDEC Standard 22, Method C101

(3) JEDEC Standard 22, Method A115-A

THERMAL CHARACTERISTICS

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
θ _{JA}	Junction-to-air thermal resistance	High-K thermal resistance		35		°C/W
θ _{JB}	Junction-to-board thermal resistance			15		°C/W
θ _{JC}	Junction-to-case thermal resistance			4.27		°C/W
PD	Device power dissipation	I _{LOAD} = 50 mA, R _{IN} = 0, IPO–IP7 = V ₂₄ = 30 V, RE7 = FGND, f _{CLK} = 100 MHz, I _{P-LIM} and I _{CC} = worst case with R _{LIM} = 25 kΩ			2591	mW

RECOMMENDED OPERATING CONDITIONS

		MIN	TYP	MAX	UNIT
V ₂₄	Field supply voltage	18	24	30	V
V _{IPL}	Field input low-state input voltage ⁽¹⁾	0		6	V
V _{IPH}	Field input high-state input voltage ⁽¹⁾	10		30	V
V _{IL}	Logic low-state input voltage	0		0.8	V
V _{IH}	Logic high-state input voltage	2		5.5	V
R _{LIM}	Current limiter resistor	17	25	500	kΩ
f _{IP}	Input data rate ⁽²⁾	0		1	Mbps
T _J				150	°C
T _A		-40		85	°C

(1) Field input voltages correspond to an input resistor of R_{IN} = 1.2 kΩ

(2) Maximum data rate corresponds to 0 ms debounce time, (DB0 = open, DB1 = FGND), and R_{IN} = 0 Ω

ELECTRICAL CHARACTERISTICS

 all voltages measured against FGND unless otherwise stated, see [Figure 12](#)

SYMBOL	PARAMETER	TERMINAL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{TH-(IP)}$	Low-level device input threshold voltage	IP0-IP7	18 V < V ₂₄ < 30 V, R _{IN} = 0 Ω	4	4.3		V
$V_{TH+(IP)}$	High-level device input threshold voltage				5.2	5.5	V
$V_{HYS(IP)}$	Device input hysteresis				0.9		V
$V_{TH-(IN)}$	Low-level field input threshold voltage	measured at field side of R _{IN}	18 V < V ₂₄ < 30 V, R _{IN} = 1.2 kΩ ± 5%, R _{LIM} = 25 kΩ	6	8.4		V
$V_{TH+(IN)}$	High-level field input threshold voltage				9.4	10	V
$V_{HYS(IN)}$	Field input hysteresis				1		V
$V_{TH-(V24)}$	Low-level V24-monitor threshold voltage	V24		15	16.05		V
$V_{TH+(V24)}$	High-level V24-monitor threshold voltage				16.8	18	V
$V_{HYS(V24)}$	V24-monitor hysteresis				0.75		V
R _{IP}	Input resistance	IP0-IP7	3 V < V _{IPx} < 6 V, R _{IN} = 1.2 kΩ ± 5%, R _{LIM} = 25 kΩ	1.4	1.83	2.3	kΩ
I _{IP-LIM}	Input current limit		10 V < V _{IPx} < 30 V, R _{LIM} = 25 kΩ	3.15	3.6	4	mA
V _{OL}	Logic low-level output voltage	SOP, CHOK	I _{OL} = 20 μA			0.4	V
V _{OH}	Logic high-level output voltage		I _{OH} = -20 μA	4			V
I _{IL}	Logic input leakage current	DB0, DB1, SIP, LD, CE, CLK		-50		50	μA
I _{RE-on}	RE on-state current	RE0-RE7	R _{LIM} = 25 kΩ, RE _x = FGND	2.8	3.15	3.5	mA
I _{CC(V24)}	Supply current	V24	IP0 to IP7 = V24, 5VOP = open, RE _x = FGND, All logic inputs open			8.7	mA
V _{O(5V)}	Linear regulator output voltage	5VOP	18 V < V ₂₄ < 30 V, no load	4.5	5	5.5	V
			18 V < V ₂₄ < 30 V, I _L = 50 mA	4.5	5	5.5	
I _{LIM(5V)}	Linear regulator output current limit				115		mA
ΔV ₅ /ΔV ₂₄	Line regulation	5VOP, V24	18 V < V ₂₄ < 30 V, I _L = 5 mA			2	mV/V
t _{DB}	Debounce times of input channels	IP0-IP7	DB0 = open, DB1 = FGND		0		ms
			DB0 = FGND, DB1 = open		1		
			DB0 = DB1 = open		3		
t _{DB-HL}	Voltage monitor debounce time after V24 < 15 V (CHOK turns low)	V24, CHOK			1		ms
t _{DB-LH}	Voltage monitor debounce time after V24 > 18 V (CHOK turns high)				6		ms
T _{OVER}	Over-temperature indication				150		°C
T _{SHDN}	Shutdown temperature				170		°C

TIMING REQUIREMENTS

over operating free-air temperature range (unless otherwise noted)

SYMBOL	PARAMETER	MIN	TYP	MAX	UNIT
t_{W1}	CLK pulse width See Figure 6	4			ns
t_{W2}	\overline{LD} pulse width See Figure 4	6			ns
t_{SU1}	SIP to CLK setup time See Figure 7	4			ns
t_{H1}	SIP to CLK hold time See Figure 7	2			ns
t_{SU2}	Falling edge to rising edge (\overline{CE} to CLK) setup time See Figure 8	4			ns
t_{REC}	\overline{LD} to CLK recovery time See Figure 5	2			ns
f_{CLK}	Clock pulse frequency See Figure 6	DC		100	MHz

SWITCHING CHARACTERISTICS

over operating free-air temperature range (unless otherwise noted)

SYMBOL	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{PLH1}, t_{PHL1}	CLK to SOP $C_L = 15$ pF, see Figure 6				10	ns
t_{PLH2}, t_{PHL2}	\overline{LD} to SOP $C_L = 15$ pF, see Figure 4				14	ns
t_r, t_f	Rise and fall times $C_L = 15$ pF, see Figure 6				5	ns

INPUT CHARACTERISTICS

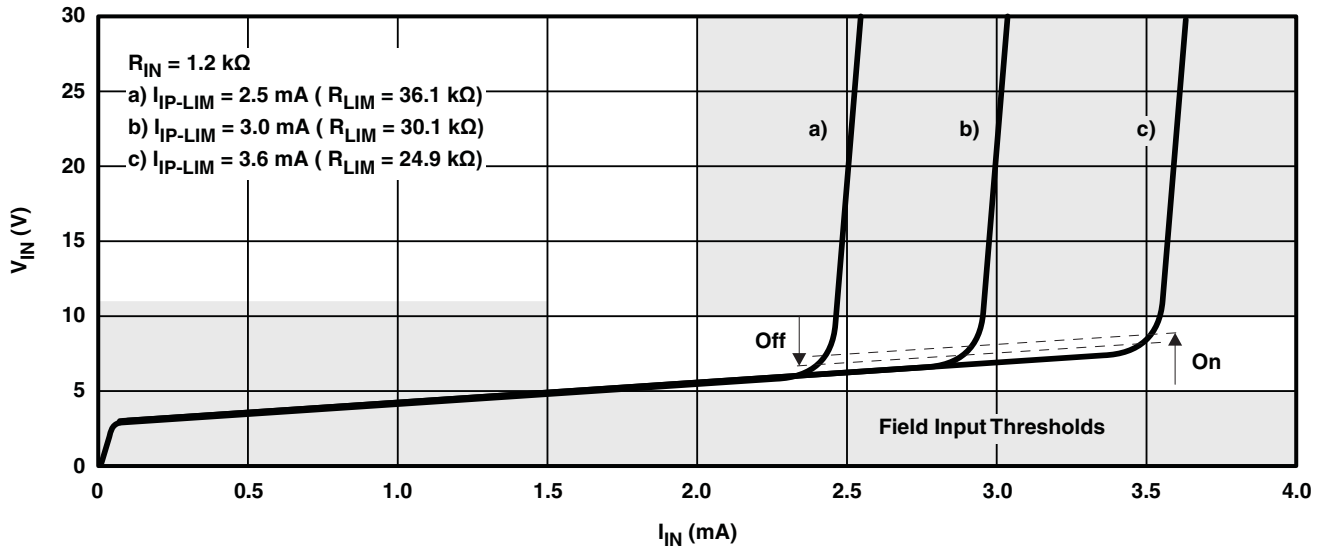


Figure 1. Typical Input Characteristics

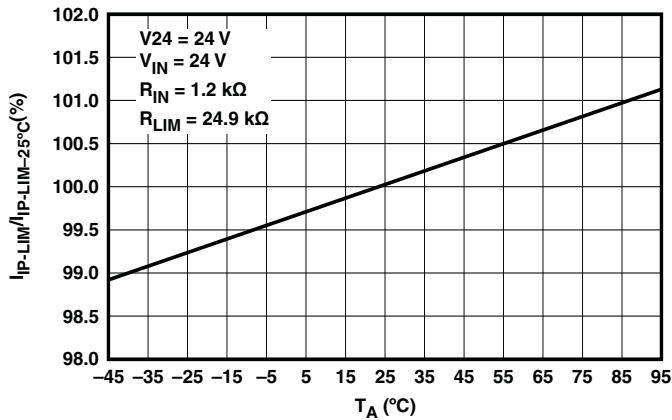


Figure 2. Typical Current Limiter Variation vs Ambient Temperature

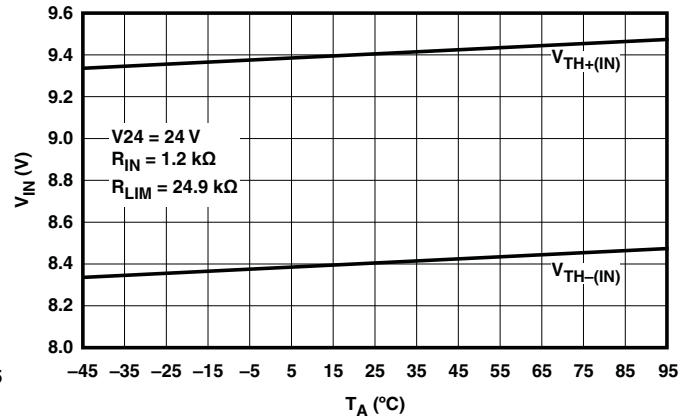


Figure 3. Typical Limiter Threshold Voltage Variation vs Ambient Temperature

PARAMETER MEASUREMENT INFORMATION

Waveforms

For the complete serial interface timing, refer to [Figure 21](#).

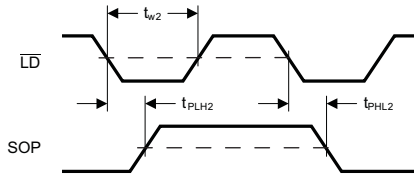


Figure 4. Parallel – Load Mode

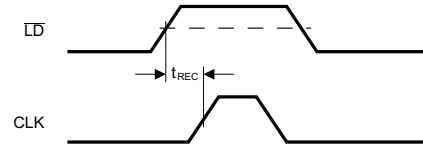


Figure 5. Serial – Shift Mode

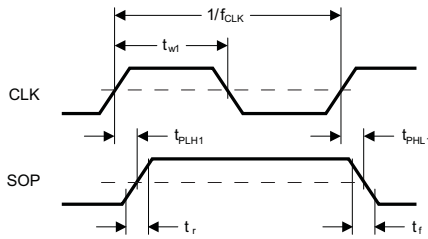


Figure 6. Serial – Shift Mode

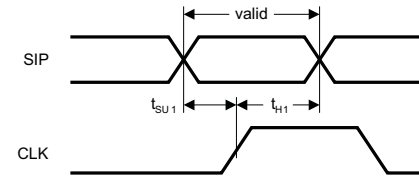


Figure 7. Serial – Shift Mode

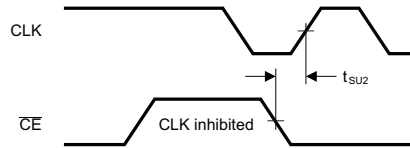


Figure 8. Serial – Shift Clock Inhibit Mode

VOLTAGE REGULATOR PERFORMANCE CHARACTERISTICS

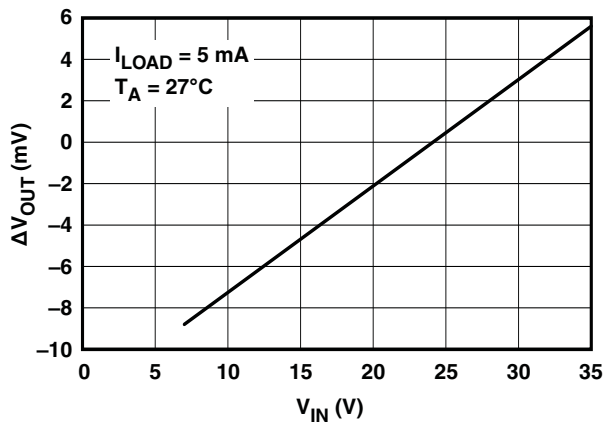


Figure 9. Line Regulation

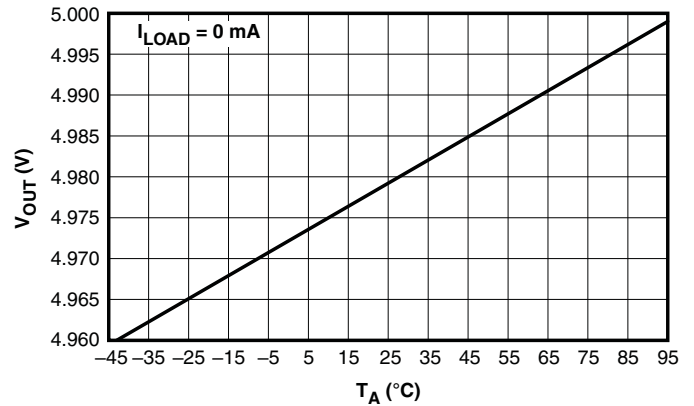


Figure 10. Output Voltage vs Ambient Temperature

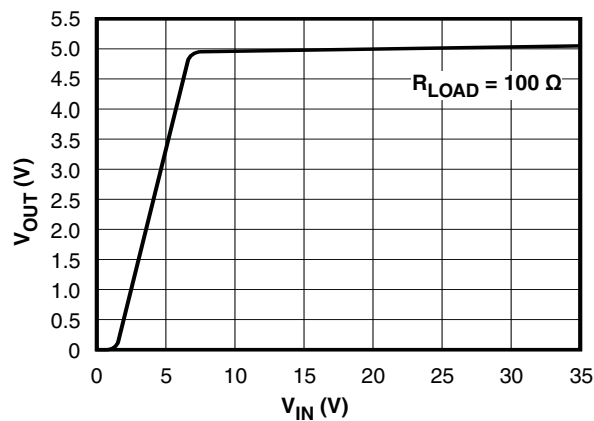


Figure 11. Output Voltage vs Input Voltage

SIGNAL CONVENTIONS

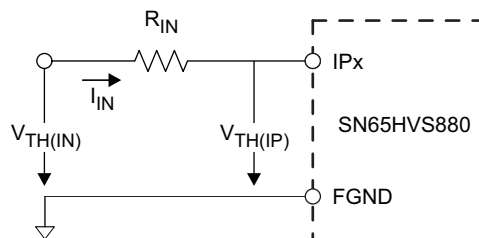


Figure 12. On/Off Threshold Voltage Measurements

DEVICE INFORMATION

Digital Inputs

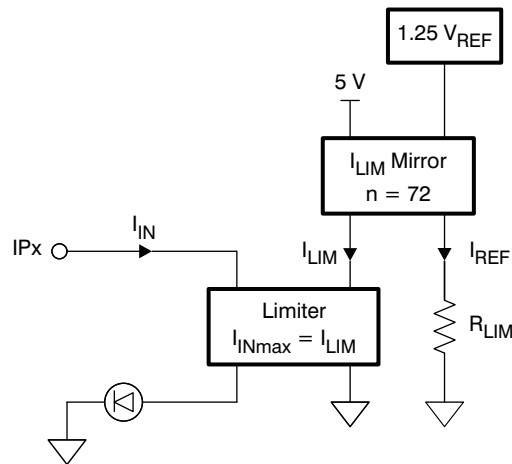


Figure 13. Digital Input Stage

Each digital input operates as a controlled current sink limiting the input current to a maximum value of I_{LIM} . The current limit is derived from the reference current via $I_{LIM} = n \times I_{REF}$, and I_{REF} is determined by $I_{REF} = V_{REF}/R_{LIM}$. Thus, changing the current limit requires the change of R_{LIM} to a different value via: $R_{LIM} = n \times V_{REF}/I_{LIM}$.

Inserting the actual values for n and V_{REF} gives: $R_{LIM} = 90 \text{ V} / I_{LIM}$.

While the device is specified for a current limit of **3.6 mA**, (via $R_{LIM} = 25 \text{ k}\Omega$), it is easy to lower the current limit to further reduce the power consumption. For example, for a current limit of **2.5 mA** simply calculate:

$$R_{LIM} = \frac{90 \text{ V}}{I_{LIM}} = \frac{90 \text{ V}}{2.5 \text{ mA}} = 36 \text{ k}\Omega$$

Debounce Filter

The HVS880 applies a simple analog/digital filtering technique to remove unintended signal transitions due to contact bounce or other mechanical effects. Any new input (either low or high) must be present for the duration of the selected debounce time to be latched into the shift register as a valid state.

The logic signal levels at the control inputs, DB0 and DB1 of the internal Debounce-Select logic determine the different debounce times listed in the following truth table.

Table 1. Debounce Times

DB1	DB0	FUNCTION
Open	Open	3 ms delay
Open	FGND	1 ms delay
FGND	Open	0 ms delay (Filter bypassed)
FGND	FGND	Reserved

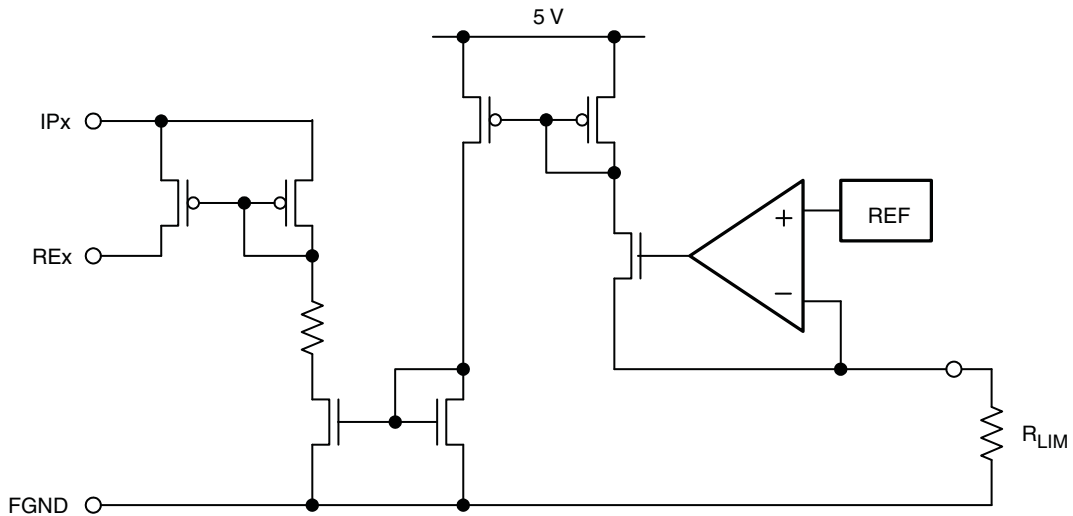


Figure 14. Equivalent Input Diagram

Shift Register

The conversion from parallel input to serial output data is performed by an eight-channel, parallel-in serial-out shift register. Parallel-in access is provided by the internal inputs, PIP0–PIP7, that are enabled by a low level at the load input (\overline{LD}). When clocked, the latched input data shift towards the serial output (SOP). The shift register also provides a clock-enable function.

Clocking is accomplished by a low-to-high transition of the clock (CLK) input while \overline{LD} is held high and the clock enable (\overline{CE}) input is held low. Parallel loading is inhibited when \overline{LD} is held high. The parallel inputs to the register are enabled while \overline{LD} is low independently of the levels of the CLK, \overline{CE} , or serial (SIP) inputs.

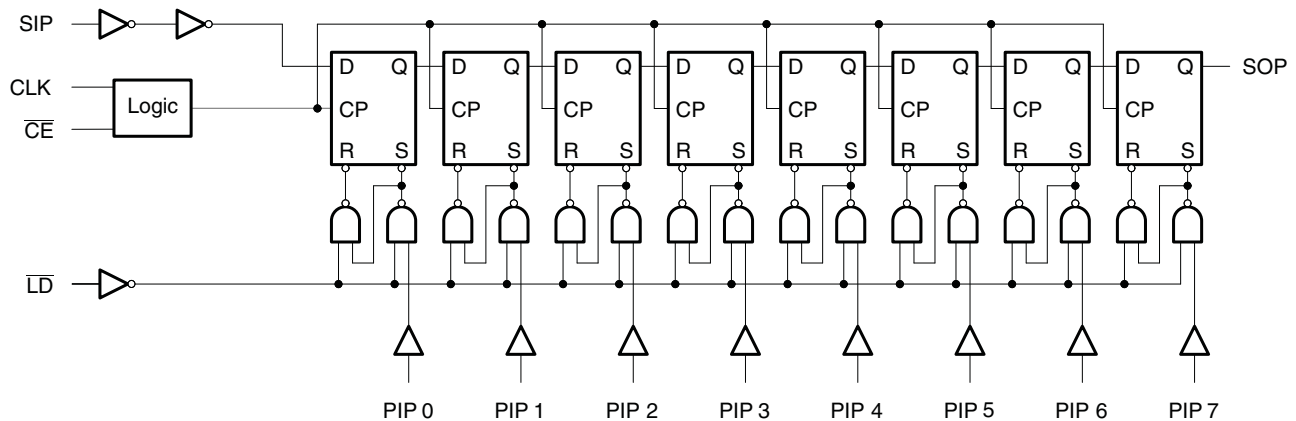


Figure 15. Shift Register Logic Structure

Table 2. Function Table

INPUTS			FUNCTION
$\overline{\text{LD}}$	CLK	$\overline{\text{CE}}$	
L	X	X	Parallel load
H	X	H	No change
H	↑	L	Shift ⁽¹⁾

(1) Shift = content of each internal register shifts towards serial outputs. Data at SIP is shifted into first register.

Voltage Regulator

The on-chip linear voltage regulator provides a 5 V supply to the internal- and external circuitry, such as digital isolators, with an output drive capability of 50 mA and a typical current limit of 115 mA. The regulator accepts input voltages from 30 V down to 10 V. Because the regulator output is intended to supply external digital isolator circuits proper output voltage decoupling is required. For best results connect a 1 μF and a 0.1 μF ceramic capacitor as close as possible to the 5VOP-output. For longer traces between the SN65HVS880 and isolators of the ISO72xx family use additional 0.1 μF and 10 pF capacitors next to the isolator supply pins. Make sure, however, that the total load capacitance does not exceed 4.7 μF .

For good stability the voltage regulator requires a minimum load current, $I_{L\text{-MIN}}$. Ensure that under any operating condition the ratio of the minimum load current in mA to the total load capacitance in μF is larger than 1:

$$\frac{I_{L\text{-MIN}}}{C_L} > \frac{1 \text{ mA}}{1 \mu\text{F}}$$

Supply Voltage Monitor

The integrated supply voltage monitor senses the supply voltage of the SN65HVS880 at the V24-pin. If this voltage drops below 15 V but stays within the regulator's operating range, i.e., $15 \text{ V} > V24 > 10 \text{ V}$, the output CHOK goes low 1 ms later. When the supply voltage returns to 24 V, the CHOK output turns logic high after 6 ms. Should the supply voltage drop below 10 V, the device ceases operation. Upon the supply returning to above 18 V, the CHOK output turns high again after 6 ms.

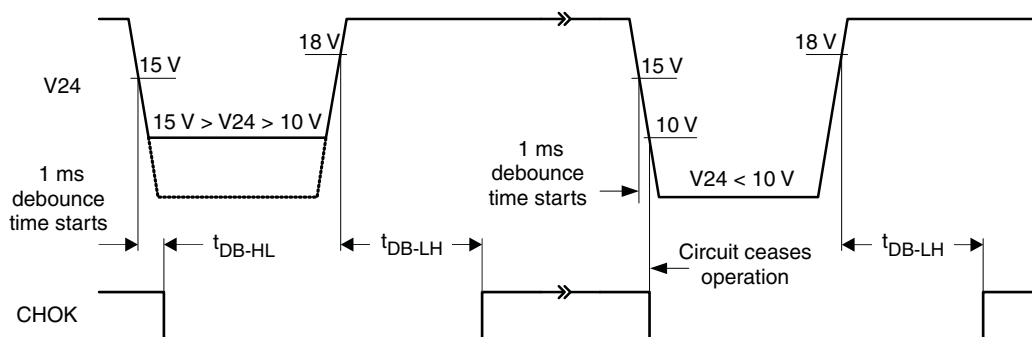


Figure 16. CHOK Output Timing as a Function of Supply Voltage Drop at V24

Temperature Sensor

An on-chip temperature sensor monitors the device temperature and signals a fault condition if the device becomes too hot. A first trip point exists at 150°C. If the junction temperature exceeds this trip point, the sensor output, being active low, presents a low to the input of the AND gate forcing the CHOK output to go low. If the junction temperature continues to rise, passing a second trip point at 170°C, all device outputs assume tri-state.

Chip Okay (CHOK) Output

The CHOK output is the Boolean AND-function of the two, active-low fault conditions: temperature failure and supply failure. As such CHOK is a device health indicator, assuming logic high in the absence of any fault condition. If either one of the two or both fault conditions occur, CHOK becomes logic low.

A special condition occurs, however, when the chip temperature exceeds the second temperature trip point due to an output short. Then the CHOK output buffer becomes tri-state, thus separating the buffer from the external circuitry. An internal 100 k Ω pulldown resistor, connecting the CHOK-pin to ground, is used as a “cooling down” resistor, which continues to provide a logic low level to the external circuitry.

APPLICATION INFORMATION

System-Level EMC

The SN65HVS880 must operate reliably in harsh industrial environments. At a system level, the device is tested according to several international electromagnetic compatibility (EMC) standards.

In addition to the device internal ESD structures, external protection circuitry, such as the one in Figure 17, is needed to absorb as much energy from burst- and surge-transients as possible.

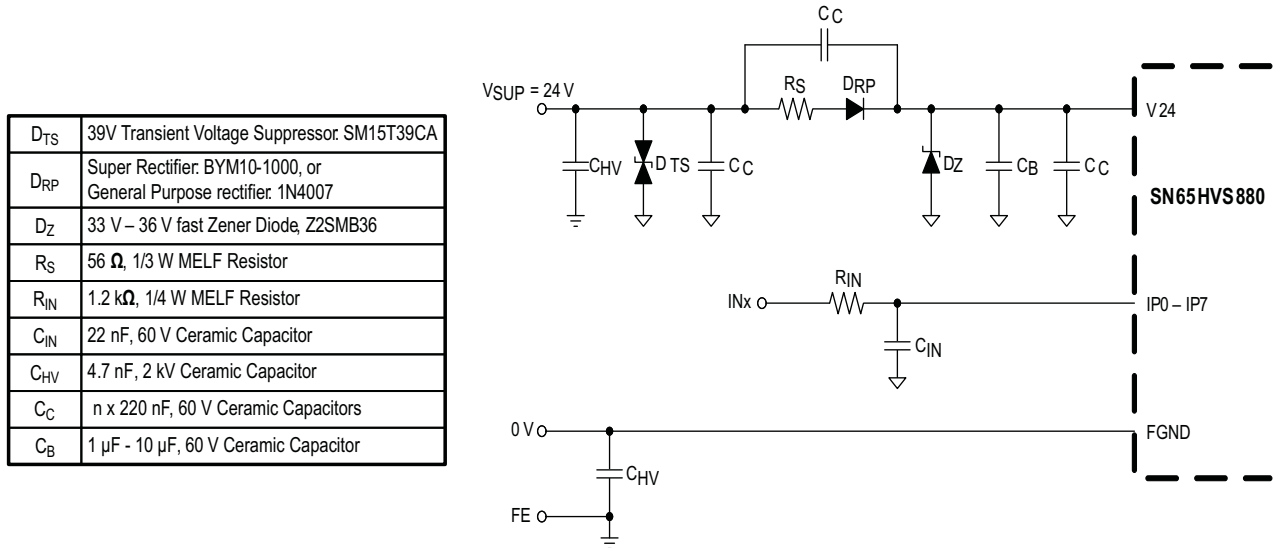


Figure 17. Typical EMC Protection Circuitry for Supply and Signal Inputs

Input Channel Switching Characteristics

The input stage of the HVS880 is so designed, that for an input resistor R_{IN} = 1.2 kΩ the trip point for signalling an ON-condition is at 9.4 V at 3.6 mA. This trip point satisfies the switching requirements of IEC61131-2 Type 1 and Type 3 switches.

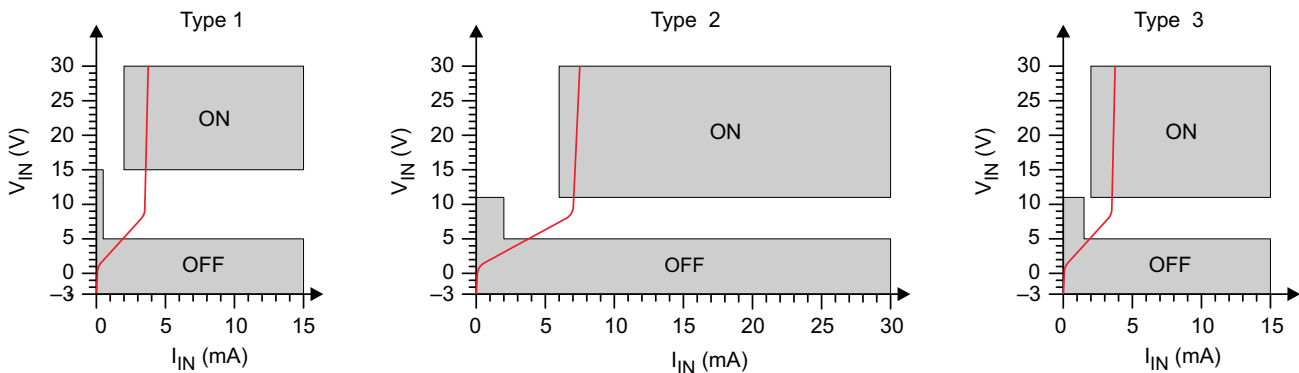


Figure 18. Switching Characteristics for IEC61131-2 Type 1, 2, and 3 Proximity Switches

For a Type 2 switch application, two inputs are connected in parallel. The current limiters then add to a total maximum current of 7.2 mA. While the return-path (RE-pin), of one input might be used to drive an indicator LED, the RE-pin of the other input channel should be connected to ground (FGND).

Paralleling input channels reduces the number of available input channels from an octal Type 1 or Type 3 input to a quad Type 2 input device. Note, that in this configuration output data of an input channel is represented by two shift register bits.

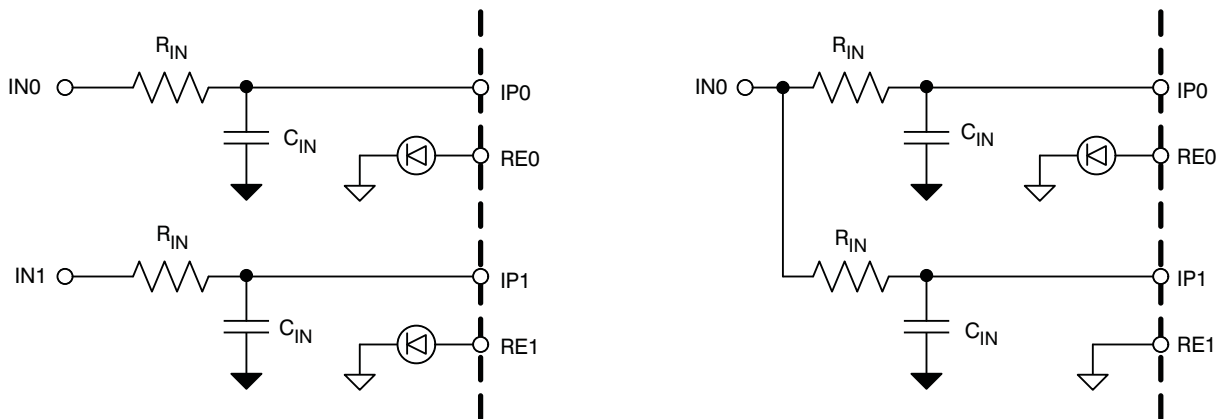


Figure 19. Paralleling Two Type 1 or Type 3 Inputs Into One Type 2 Input

Digital Interface Timing

The digital interface of the SN65HVS880 is SPI compatible and interfaces, isolated or non-isolated, to a wide variety of standard micro controllers.

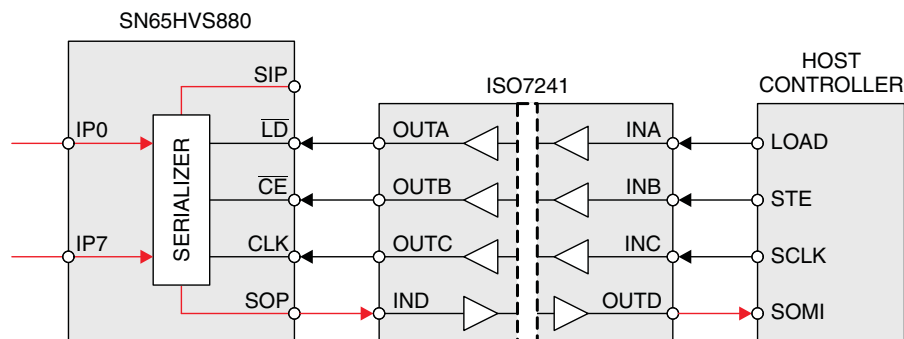


Figure 20. Simple Isolation of the Shift Register Interface

Upon a low-level at the load input, \overline{LD} , the information of the field inputs, IP0 to IP7 is latched into the shift register. Taking \overline{LD} high again blocks the parallel inputs of the shift register from the field inputs. A low-level at the clock-enable input, \overline{CE} , enables the clock signal, CLK, to serially shift the data to the serial output, SOP. Data is clocked at the rising edge of CLK. Thus after eight consecutive clock cycles all field input data have been clocked out of the shift register and the information of the serial input, SIP, appears at the serial output, SOP.

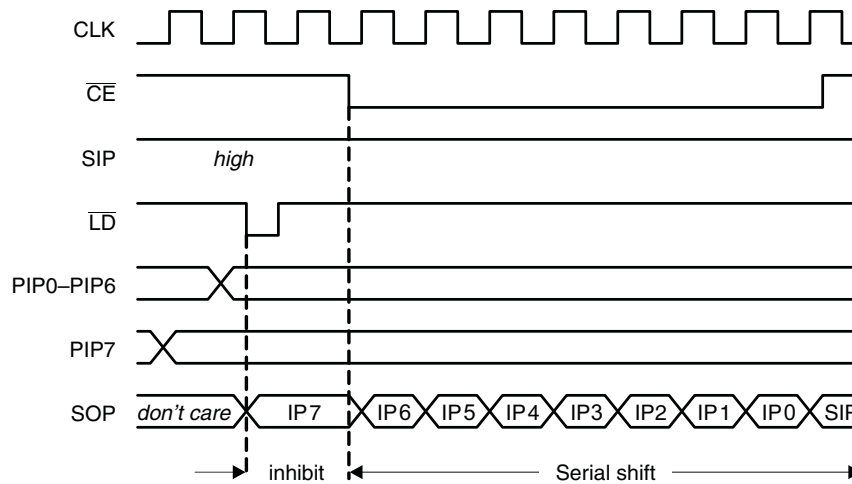


Figure 21. Interface Timing for Parallel-Load and Serial-Shift Operation of the Shift Register

Cascading for High Channel Count Input Modules

Designing high-channel count modules require cascading multiple SN65HVS880 devices. Simply connect the serial output (SOP) of a leading device with the serial input (SIP) of a following device without changing the processor interface.

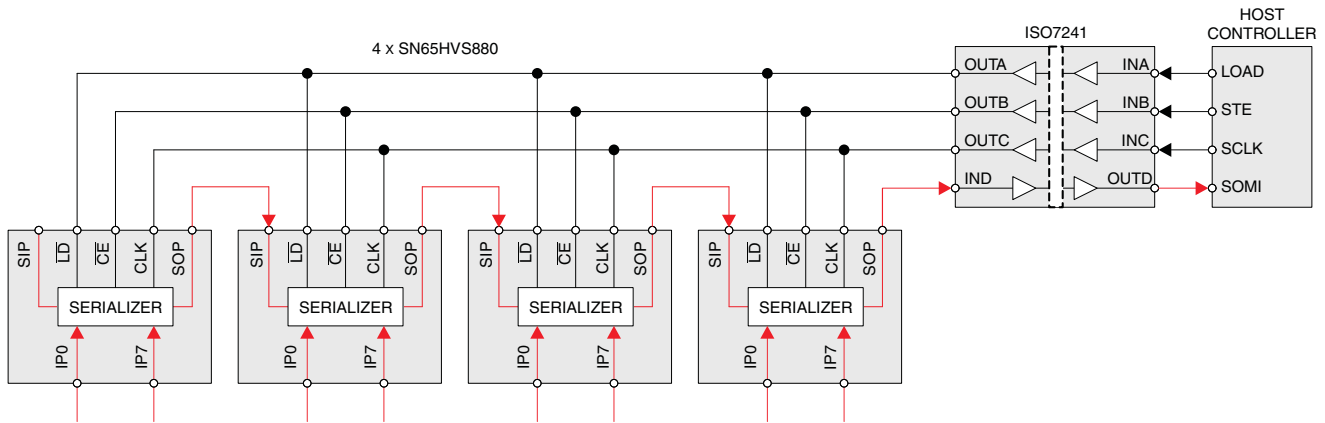


Figure 22. Cascading Four SN65HVS880 for a 32-Channel Input Module

Typical Digital Input Module Application

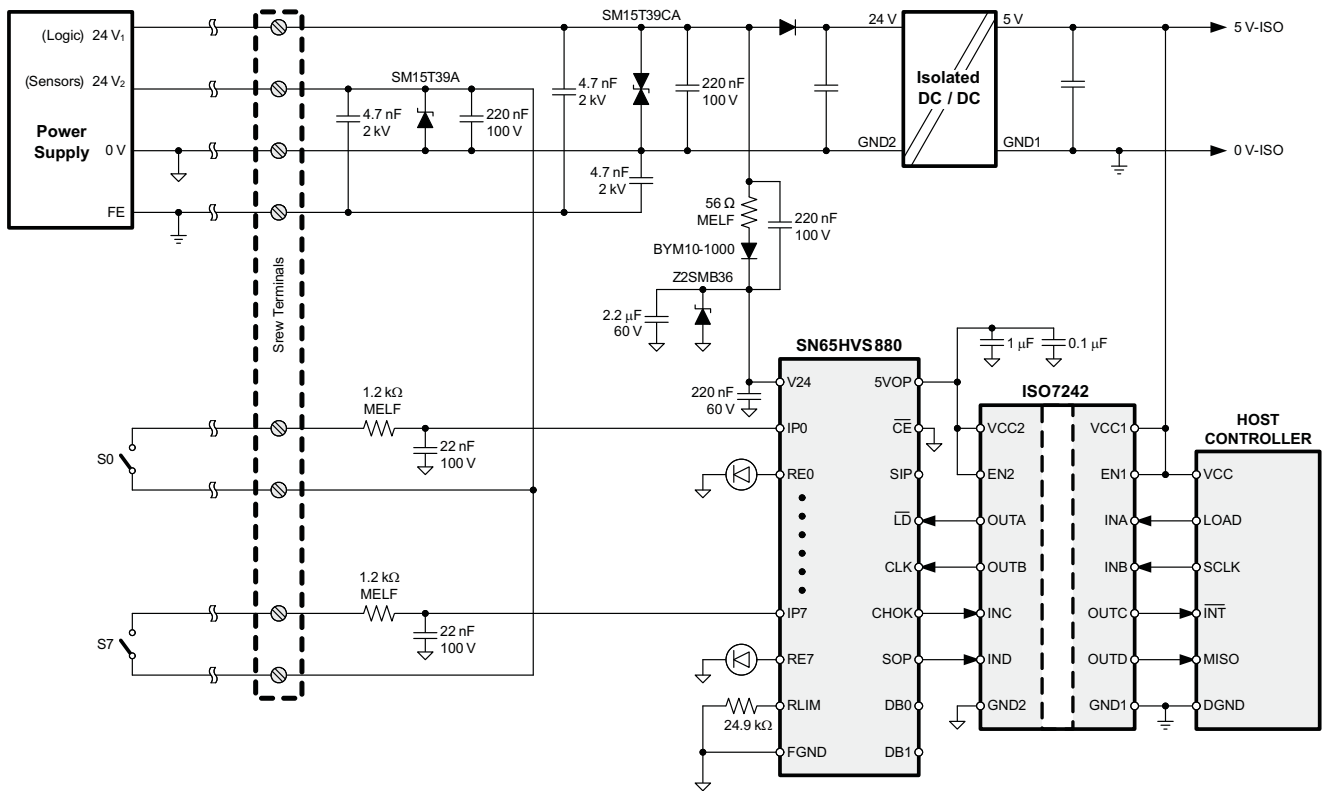


Figure 23. Typical Digital Input Module Application

PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
SN65HVS880PWP	ACTIVE	HTSSOP	PWP	28	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
SN65HVS880PWPG4	ACTIVE	HTSSOP	PWP	28	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
SN65HVS880PWPR	ACTIVE	HTSSOP	PWP	28	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
SN65HVS880PWPRG4	ACTIVE	HTSSOP	PWP	28	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check <http://www.ti.com/productcontent> for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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TAPE AND REEL INFORMATION
REEL DIMENSIONS

TAPE DIMENSIONS


A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

TAPE AND REEL INFORMATION

*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN65HVS880PWPR	HTSSOP	PWP	28	2000	330.0	16.4	6.9	10.2	1.8	12.0	16.0	Q1

TAPE AND REEL BOX DIMENSIONS



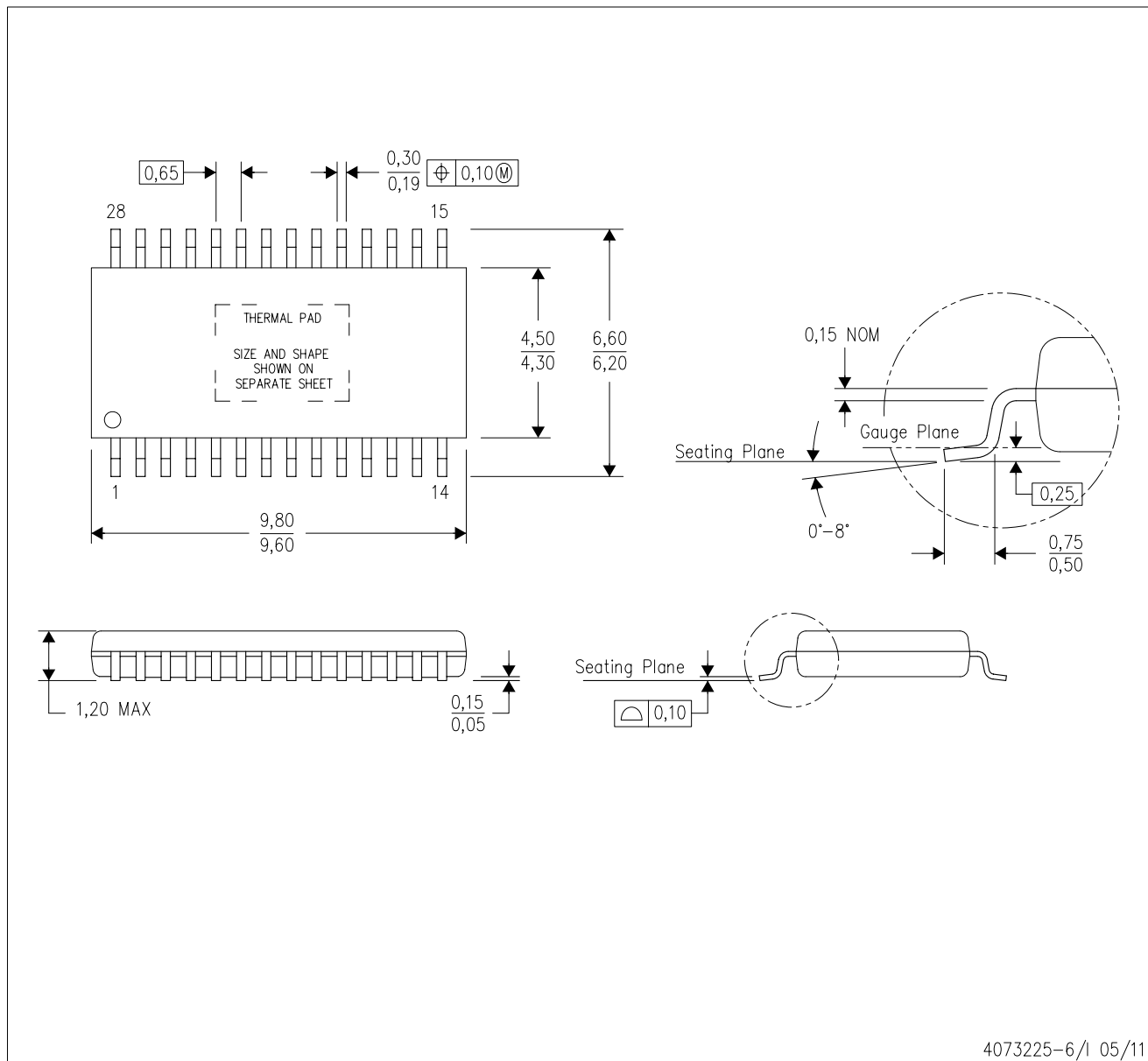
*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN65HVS880PWPR	HTSSOP	PWP	28	2000	367.0	367.0	38.0

MECHANICAL DATA

PWP (R-PDSO-G28)

PowerPAD™ PLASTIC SMALL OUTLINE



4073225-6/1 05/11

- NOTES:
- All linear dimensions are in millimeters.
 - This drawing is subject to change without notice.
 - Body dimensions do not include mold flash or protrusions. Mold flash and protrusion shall not exceed 0.15 per side.
 - This package is designed to be soldered to a thermal pad on the board. Refer to Technical Brief, PowerPad Thermally Enhanced Package, Texas Instruments Literature No. SLMA002 for information regarding recommended board layout. This document is available at www.ti.com <<http://www.ti.com>>.
 - See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
 - Falls within JEDEC MO-153

PowerPAD is a trademark of Texas Instruments.

THERMAL PAD MECHANICAL DATA

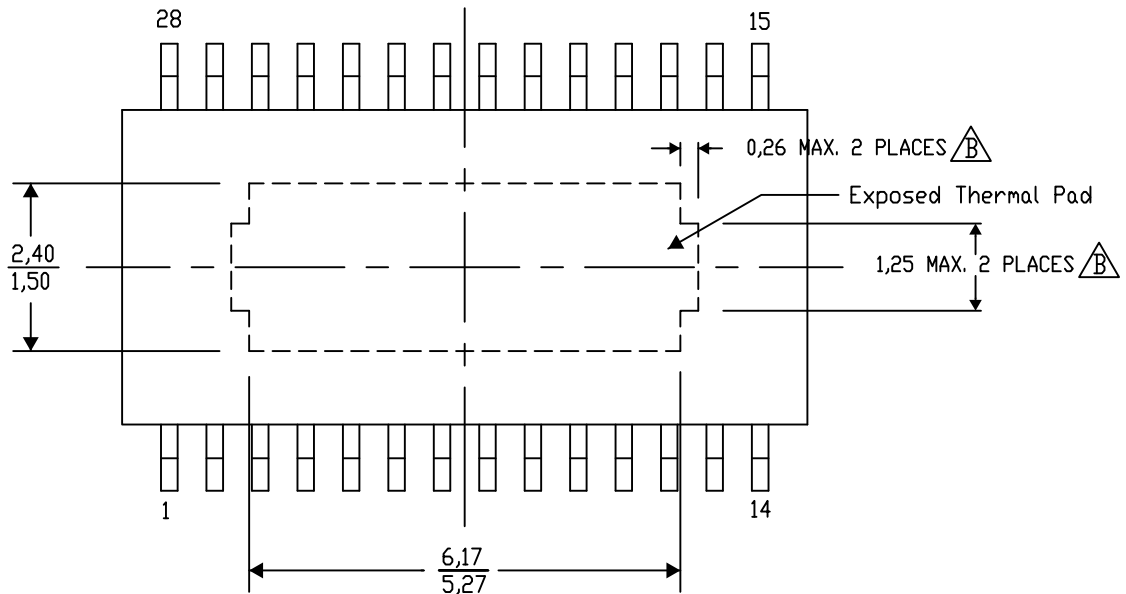
PWP (R-PDSO-G28) PowerPAD™ SMALL PLASTIC OUTLINE

THERMAL INFORMATION

This PowerPAD™ package incorporates an exposed thermal pad that is designed to be attached to a printed circuit board (PCB). The thermal pad must be soldered directly to the PCB. After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For additional information on the PowerPAD package and how to take advantage of its heat dissipating abilities, refer to Technical Brief, PowerPAD Thermally Enhanced Package, Texas Instruments Literature No. SLMA002 and Application Brief, PowerPAD Made Easy, Texas Instruments Literature No. SLMA004. Both documents are available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



Top View

Exposed Thermal Pad Dimensions

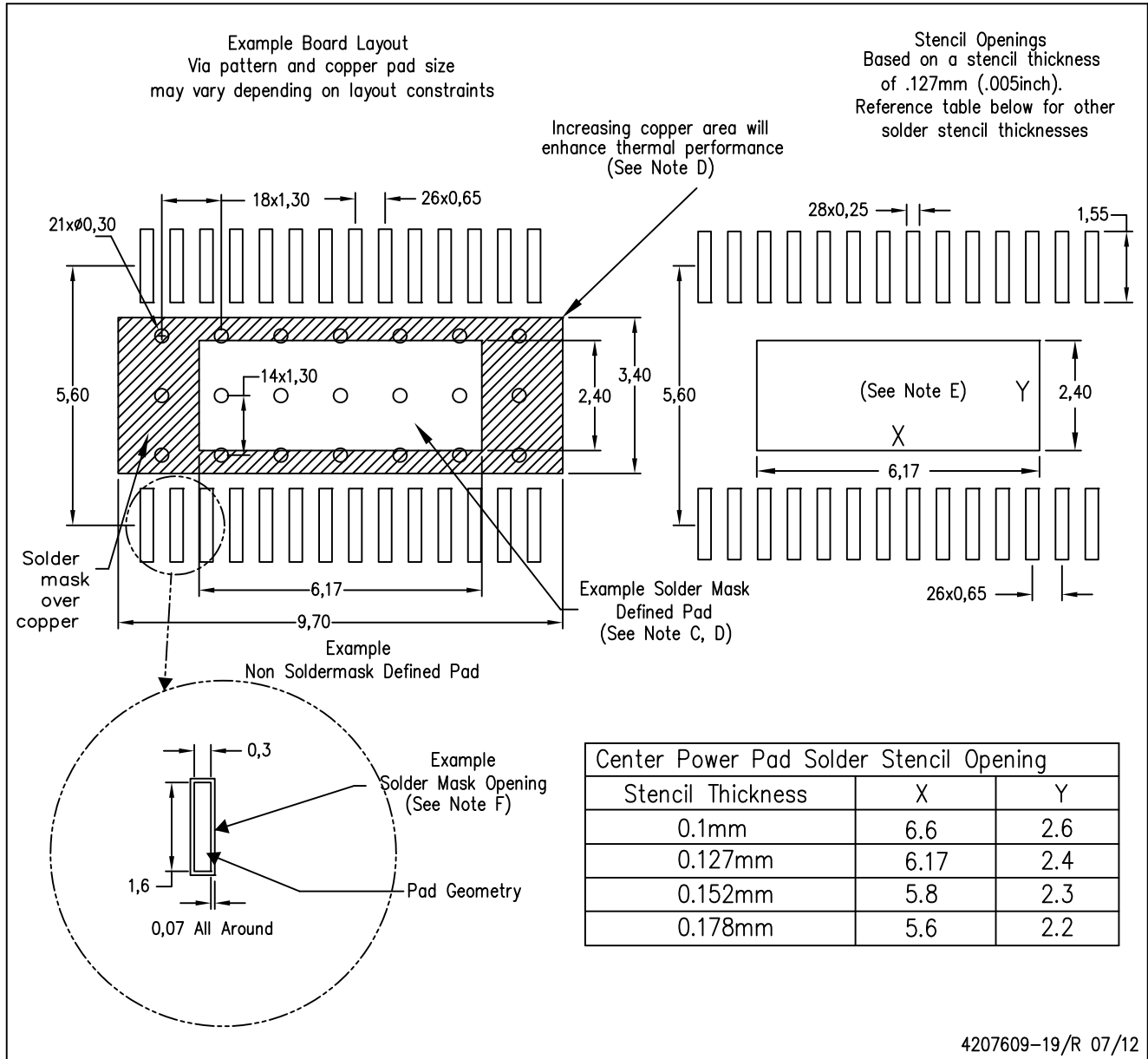
4206332-33/AC 07/12

NOTE: A. All linear dimensions are in millimeters
B. Exposed tie strap features may not be present.

PowerPAD is a trademark of Texas Instruments

PWP (R-PDSO-G28)

PowerPAD™ PLASTIC SMALL OUTLINE



- NOTES:
- All linear dimensions are in millimeters.
 - This drawing is subject to change without notice.
 - Customers should place a note on the circuit board fabrication drawing not to alter the center solder mask defined pad.
 - This package is designed to be soldered to a thermal pad on the board. Refer to Technical Brief, PowerPad Thermally Enhanced Package, Texas Instruments Literature No. SLMA002, SLMA004, and also the Product Data Sheets.
 - For specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <<http://www.ti.com>>. Publication IPC-7351 is recommended for alternate designs. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil
 - Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.

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